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12/19/01

12/03/03

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPLICATION		FILING DATE		CLASS	SUBCLASS	GAU	EXAMINER
APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER		
10025085	12/19/2001	438	636	2913 2012	T. Pham		
**APPLICANTS: Tan Cher; Mukherjee-Roy Moitreyee; Foo Pang;							
**CONTINUING DATA VERIFIED:							
** FOREIGN APPLICATIONS VERIFIED: SINGAPORE 200105179-6 08/24/2001							
PG-PUB		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>		ATTORNEY DOCKET NO.	
Foreign priority claimed		<input type="checkbox"/> yes <input type="checkbox"/> no		2085-00600 (IME-P002US)			
35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no					
Verified and Acknowledged Examiners's initials							
TITLE : Method for preventing photoresist poisoning in semiconductor fabrication							

U.S. DEPT. OF COMM. PAT. & TM. PTO-436 (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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